

## **Reliability Monitoring Results**

**Quarters:** Q1/2021 to Q4/2021 Based on structural similarity

SupplierUser Part NumberNexperia B.V.74LVC2G86GX

Part Description: Dual 2-input EXCLUSIVE-OR gate

Function Family: LVC Process family: Sub micron Package family: X2SON

JESD47		Test Conditions	Duration	# Lots	# Quantity	# Rejects
# 1	<b>TEST</b> Pre- and Post-Stress Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below
# 2	<b>PC</b> Preconditioning	JESD22-A113 MSL 1	N/A	1817	63349	0
# 5a	HTOL EFR High Temperature Operating Life Extrinsic	JESD22-A108 Tj = 150°C $V_{CCMAX} \le V \le 1.2*V_{CCMAX}$	48 hours or 168 hours	356	51713	0
# 5b	HTOL IFR High Temperature Operating Life Intrinsic	JESD22-A108 Tj = 150°C $V_{CCMAX} \le V \le 1.2*V_{CCMAX}$	≥500 hours	134	9791	0
# 7	TC Temperature Cycling	JESD22-A104 -65 °C to 150°C	≥500 cycles	940	32387	0
# 9	uHAST / HAST unbiased or biased High Accelerated Stress Test	JESD22-A101 Tamb = 130 °C, RH = 85%, V = V <sub>CCMAX</sub>	96 hours	925	30962	0

## Calculation of PPM, FIT and MTTF

Test considered for PPM calculation: High Temperature Operating LifeTest Extrinsic (HTOL EFR, Test # 5a above) Test considered for FIT and MTTF calculations: High Temperature Operating LifeTest Intrinsic(HTOL IFR, Test # 5b above)

Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

	Product Family	· · · · · · · · · · · · · · · · · · ·		Rejects	Extrinsic Failure Rate (PPM)	Intrinsic Failure Rate (FIT)	MTTF (hrs)
L	LVC	X2SON	9791	0	18	0.5	2.22 E+09